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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

10/056906
01/24/02
18/8

APPL NUM 10056906	FILING DATE 01/24/2002	CLASS 412	SUBCLASS 866.1	GAU 3552	EXAMINER CARPEN
**APPLICANTS: Renken Wayne: <i>X 13/866</i>					
**CONTINUING DATA VERIFIED:					
** FOREIGN APPLICATIONS VERIFIED:					
PG-PUB <input type="checkbox"/> DO NOT PUBLISH <input type="checkbox"/> RESCIND <input type="checkbox"/>					
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiners's initials			ATTORNEY DOCKET NO M-12467		
TITLE : Process condition sensing wafer and data analysis system					

U.S. DEPT. OF COM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Assistant Examiner	Total Claims Print Claim for O.G.
ISSUE FEE		Primary Examiner	DRAWING
Amount Due	Date Paid		Sheets Drwg. Figs. Drwg. Print Fig.
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	Application Examiner
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